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					First Named Inventor	Mei-Ling	Wu 7						
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			_		Examiner Name								
Sheet		1	of	1	Attorney Docket Number	284867-0	0040						
Examiner Initials	Cite No.		Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.										
8m		grown	KAZUHIKO ENDO ET AL., "Nitrogen doped fluorinated amorphous carbon thin films grown by plasma enhanced chemical vapor deposition for low dielectric constant interlayer dielectrics", Appl. Phys. Lett., June 17, 1996, pp. 3656-3658, Vol. 68, No. 25.										
En			T.E. KARIS ET AL., "Ellipsometric measurement of solid fluorocarbon film thickness on magnetic recording media", <i>J. Appl. Phys.</i> , April 15, 1997, pp. 5378-5380, Vol. 81, No. 8.										
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Ou		SiO ₂ :1	J. LUBGUBAN JR. ET AL., "Thermal stability and breakdown strength of carbon-doped SiO ₂ :F films prepared by plasma-enhanced chemical vapor deposition method", <i>Journal of Applied Physics</i> , April 15, 2000, pp. 3715-3722, Vol. 87, No. 8.										

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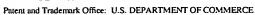
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					First Named Inventor	Mei-Ling Wu		
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				U.S. PATENT DOCUMEN	rs	
Examiner Initials	Cite No.1	U.S. Patent Document Number	Kind Code ²	Name of Patente or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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Ru	1	4,693,799		Yanagihara et al.	09-15-1987	
RIL		5,674,638		Grill et al.	10-07-1997	
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